# STATISTICAL VERIFICATION OF ANALOG CIRCUITS

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• Behavioral verification



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- A lot of exciting progress
- Transistor-level



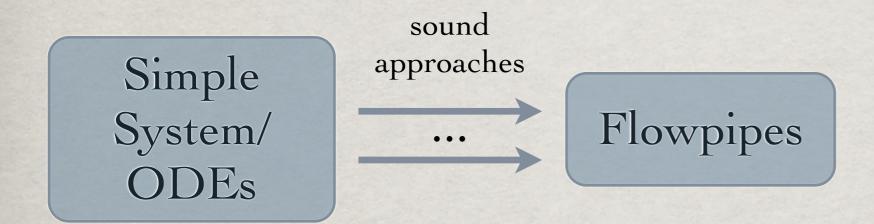
- Over-simplified device models
- Unverified higher-level abstraction, e.g., op-amp models

#### ABOUT THIS TALK

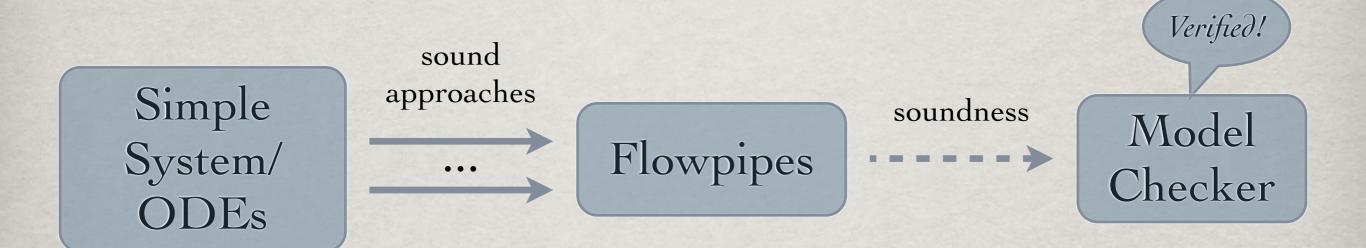
- Focus on transistor-level circuits
  - Variations: process, voltage, temperature
- Introduce a statistical verification approach
  - Verify interesting properties
  - Provide useful information to designers

Simple
System/
ODEs

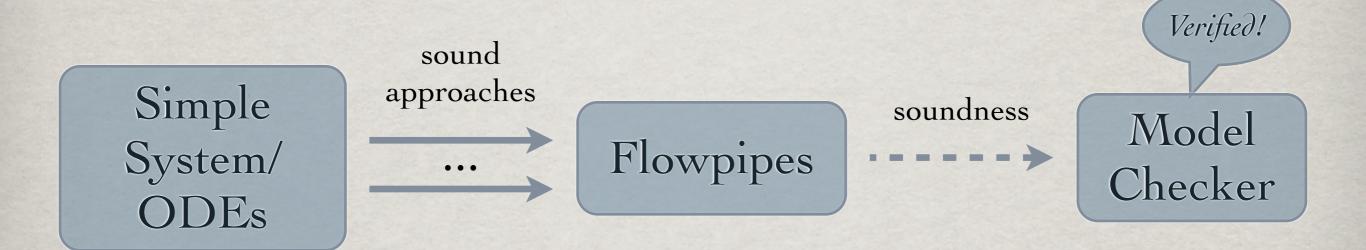
Complicated
System/
Blackbox

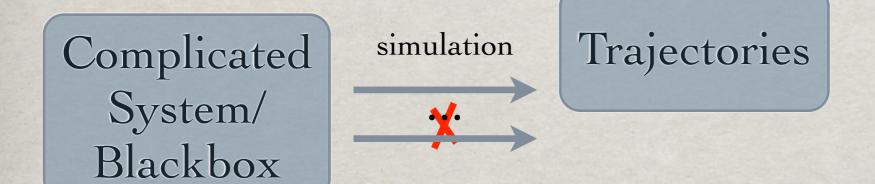


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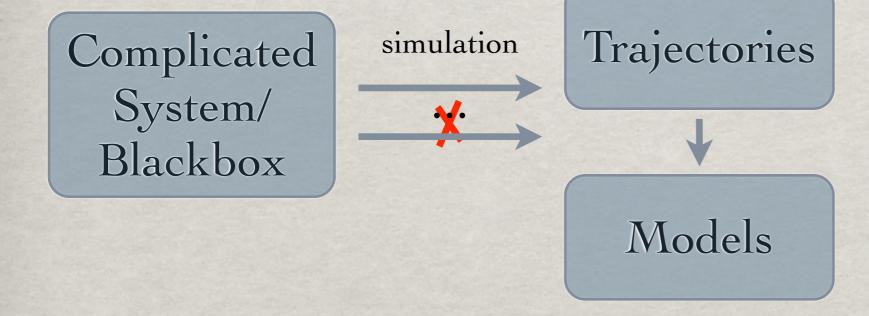


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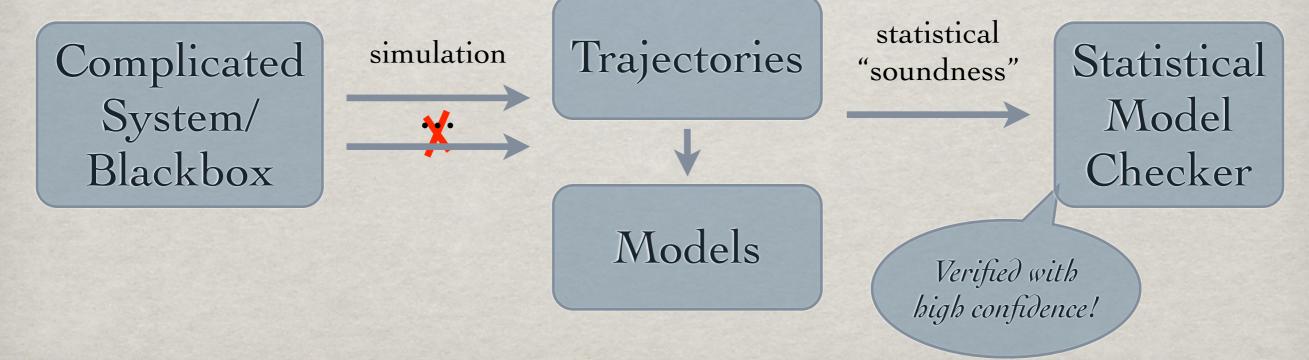


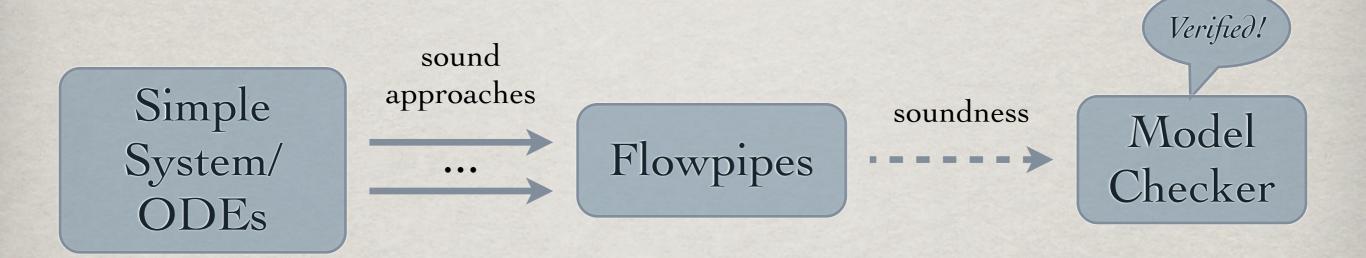


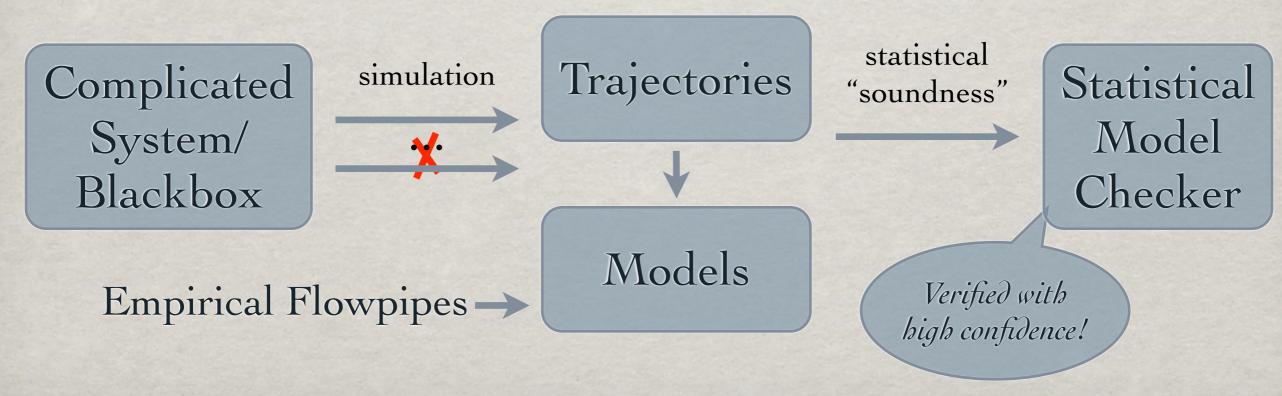


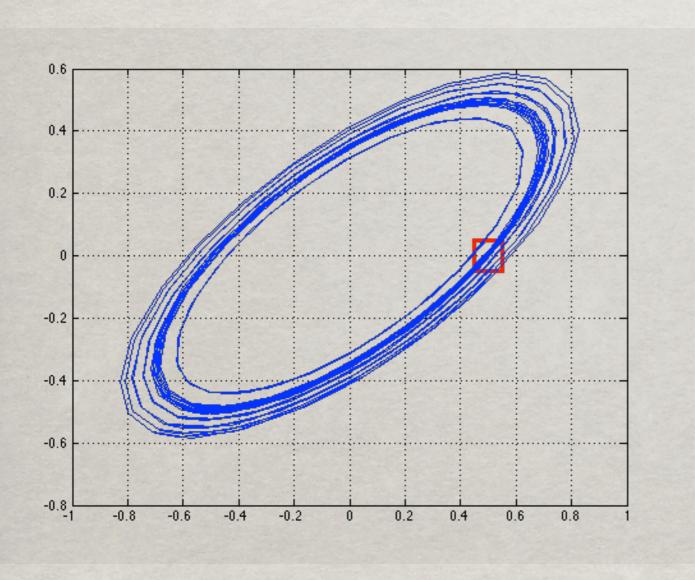




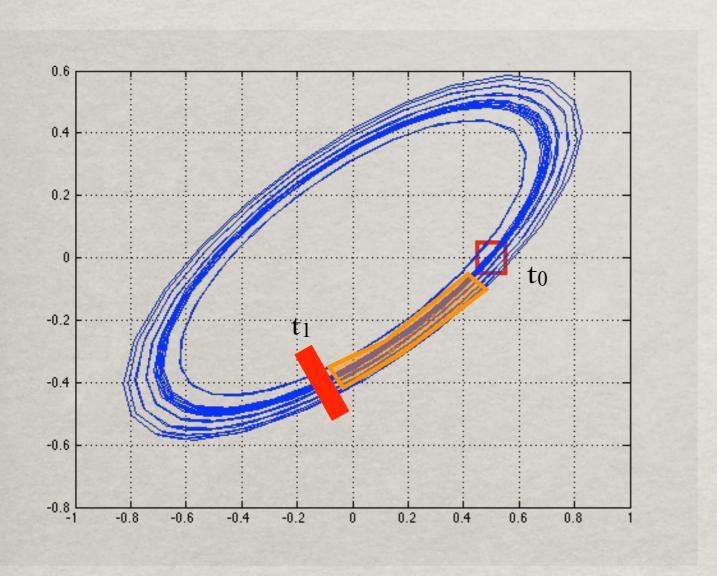






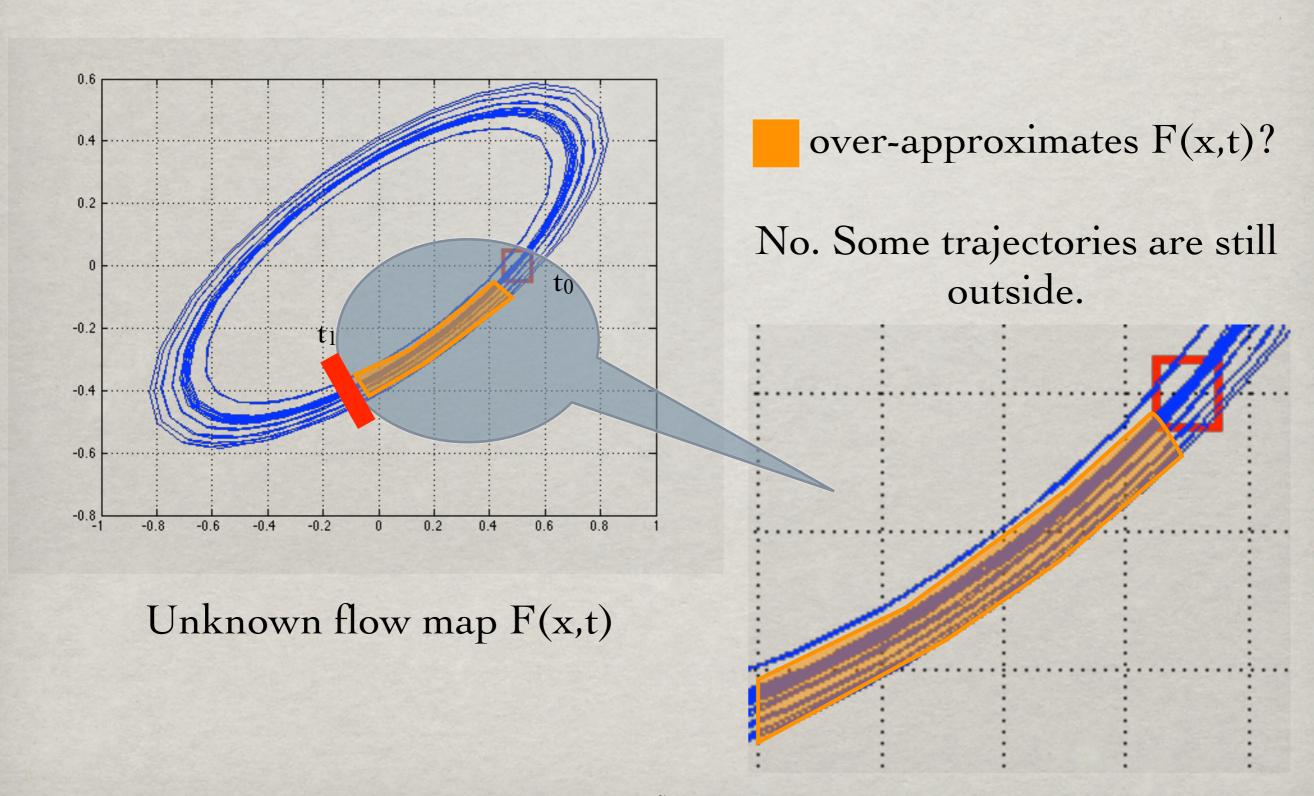


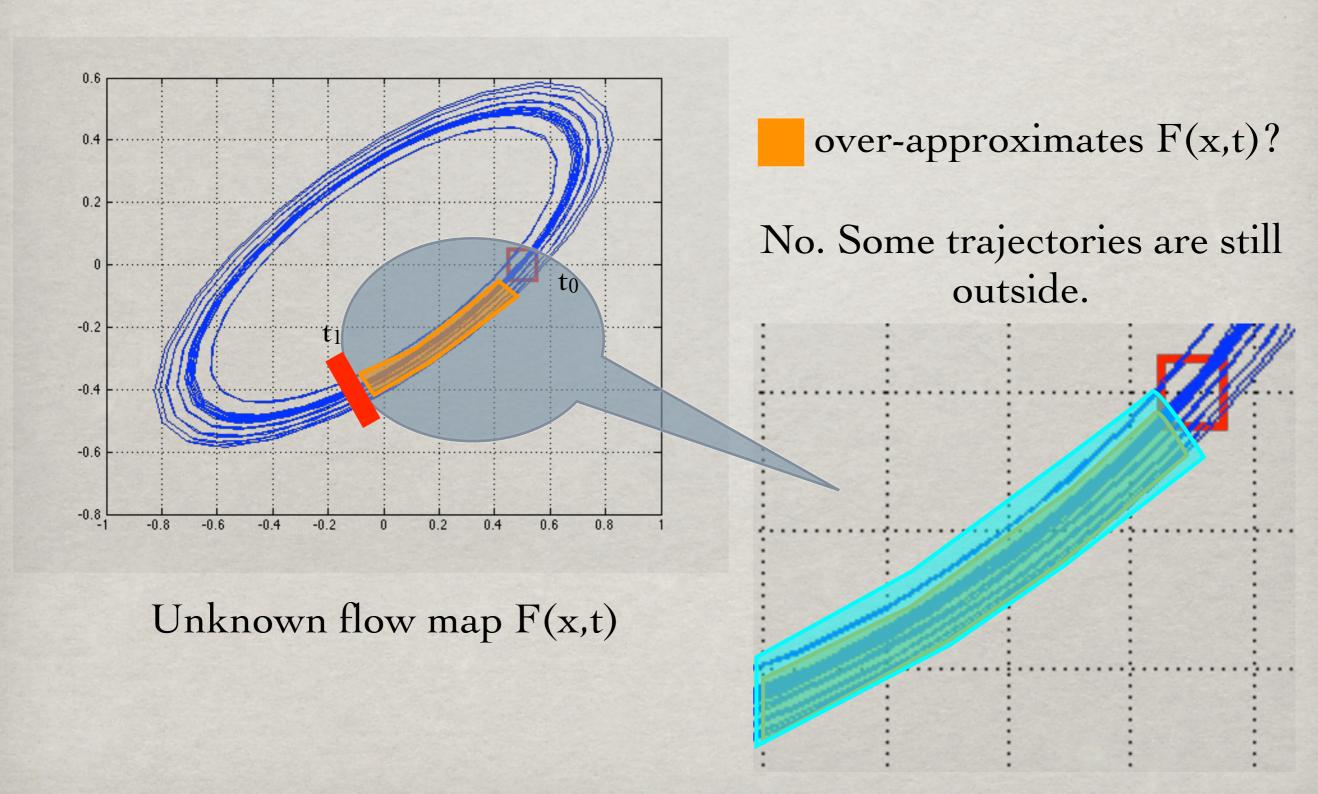
Unknown flow map F(x,t)

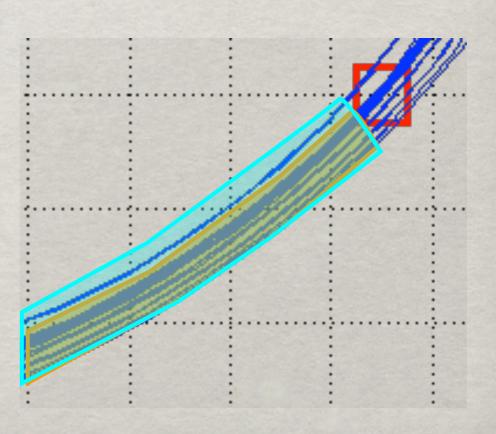


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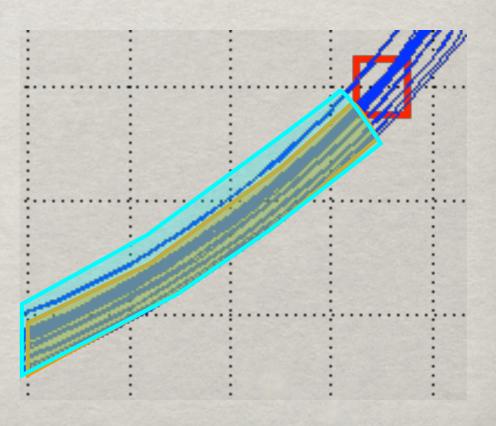
over-approximates F(x,t)?





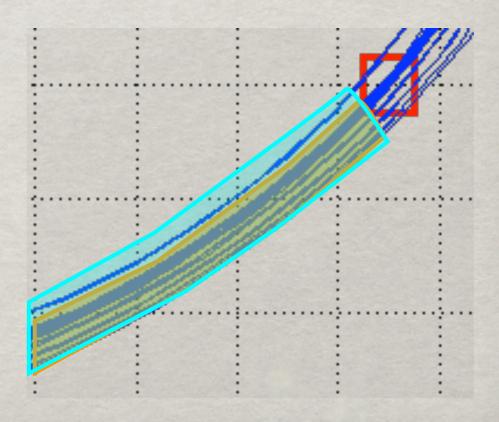


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- Alternatively, = (I + I)

$$\varphi = \forall x \in [t_0, t_1].F(x,t)$$
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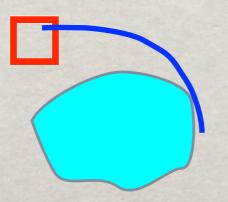
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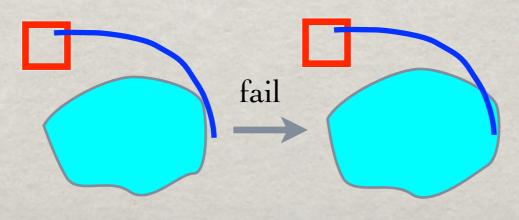
- Ask whether  $\models P_{(\geq 0.99)}(\varphi)$ 
  - A statistical model checking (SMC) problem

- Hypothesis test:  $H_0$ :  $p \ge 0.99$  vs  $H_1$ : p < 0.99
  - Sequential probability ratio test (Younes et. al)
  - Sequential Bayesian test (Clarke et. al)

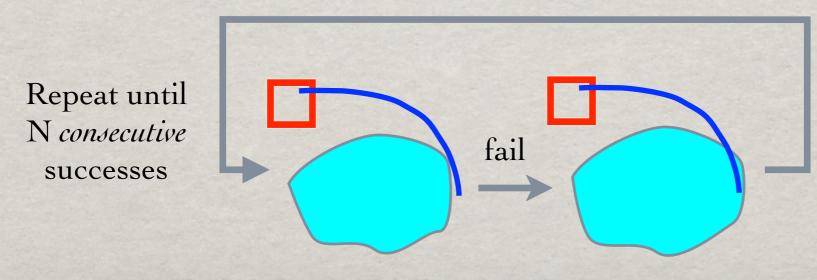
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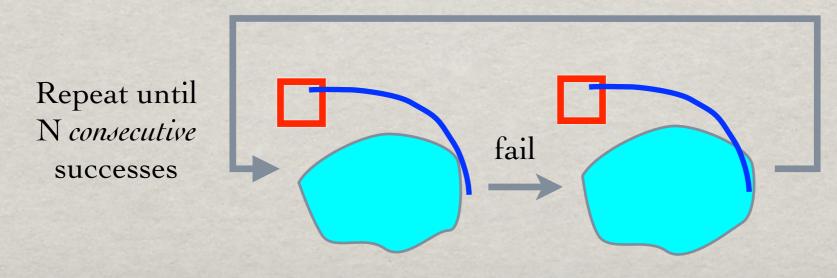
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- Outcome: accept/reject H<sub>0</sub> with specified confidence (usually high, e.g., 0.99)



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• Sample and simulate

Compute models to approximate dynamics

• Bloat models for over-approximation

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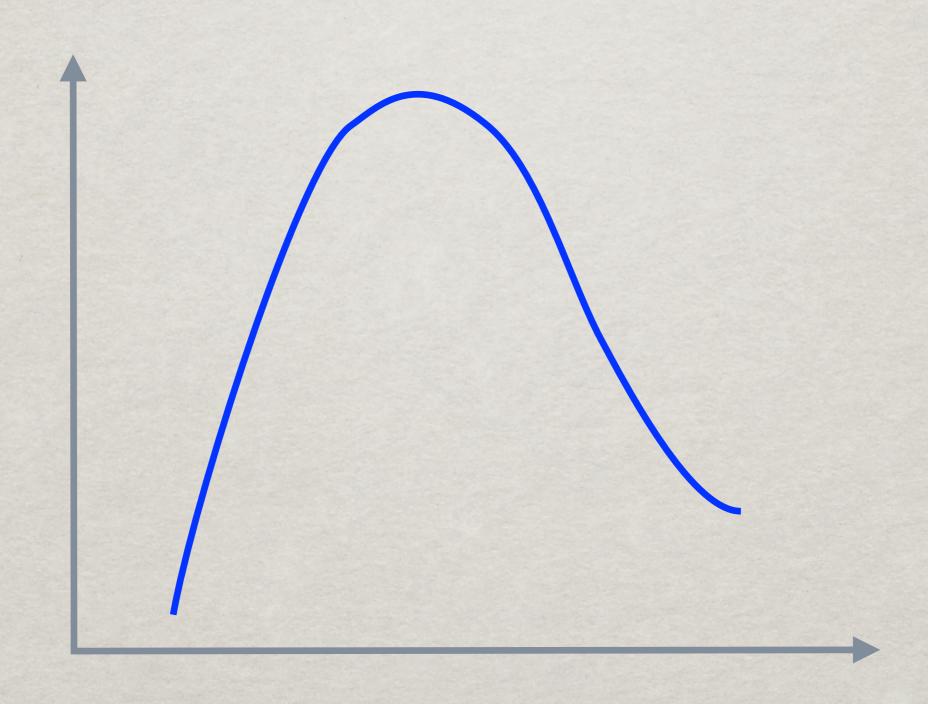
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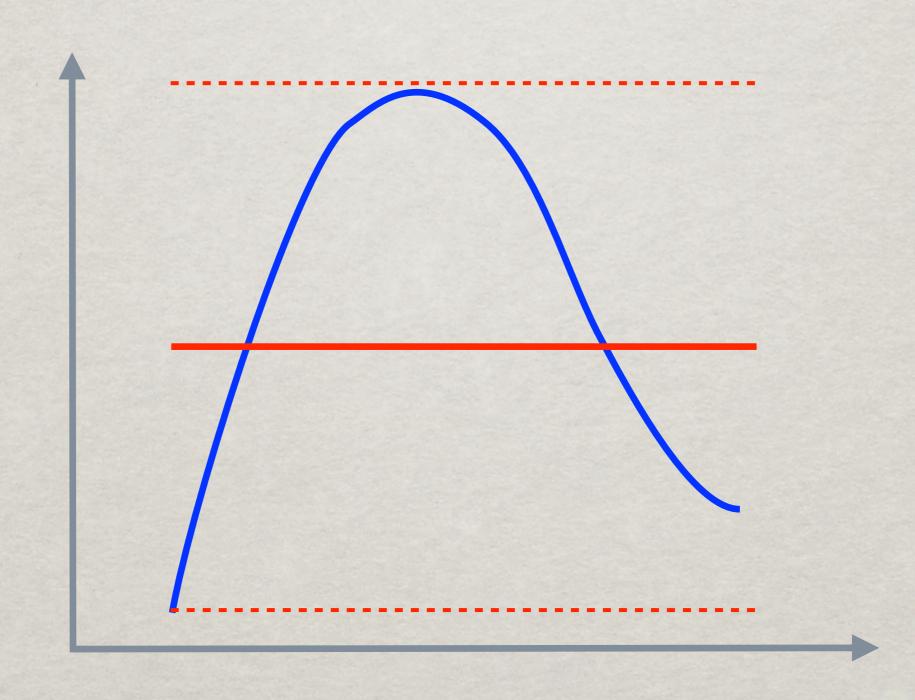
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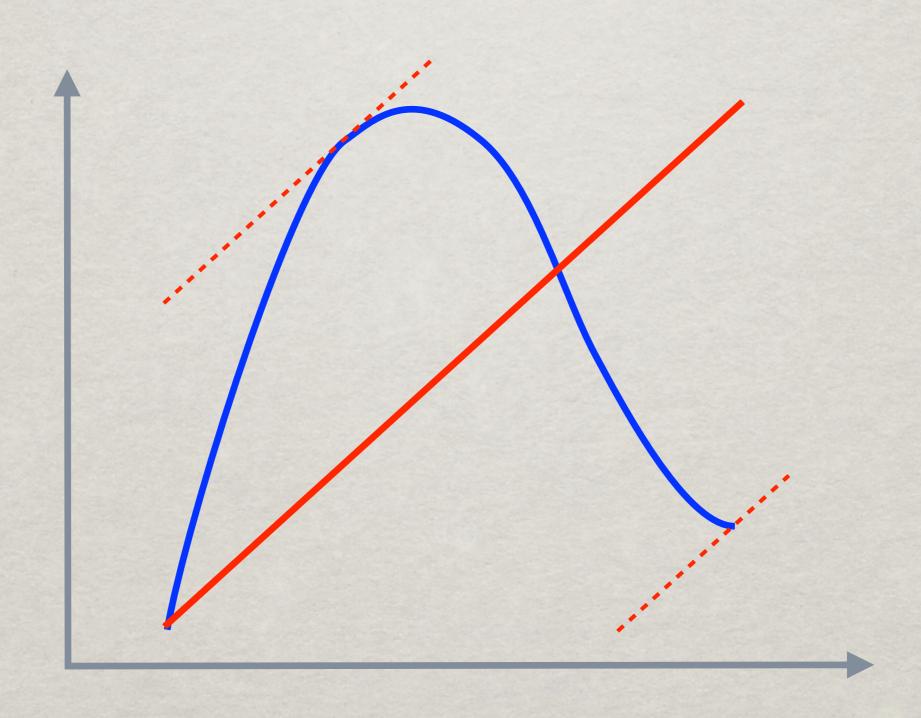


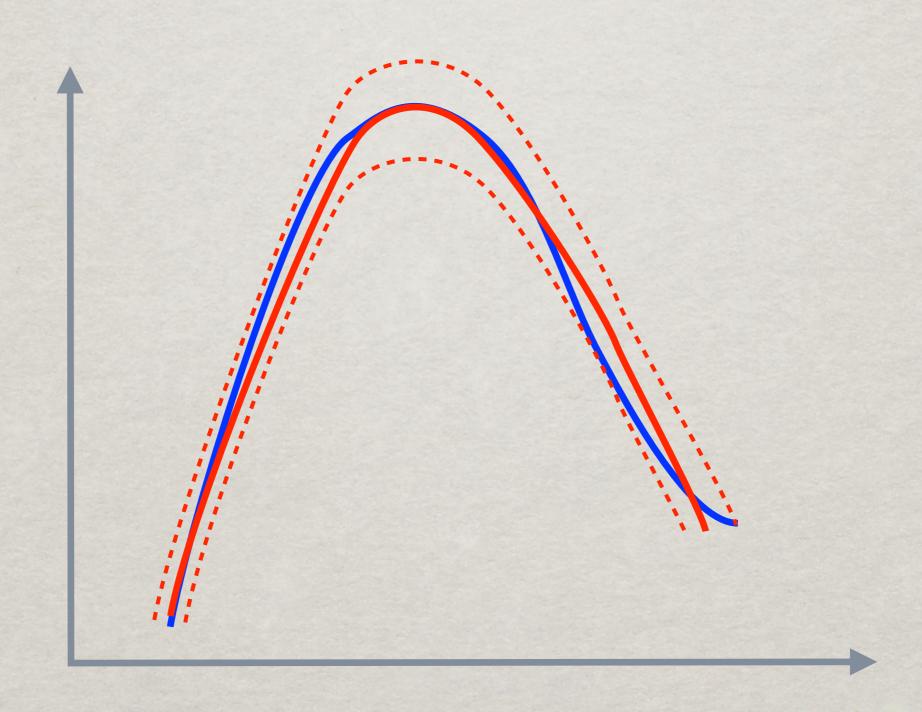
- Compute models to approximate dynamics
  - Taylor models (p, I) (Berz et. al)
- Bloat models for over-approximation

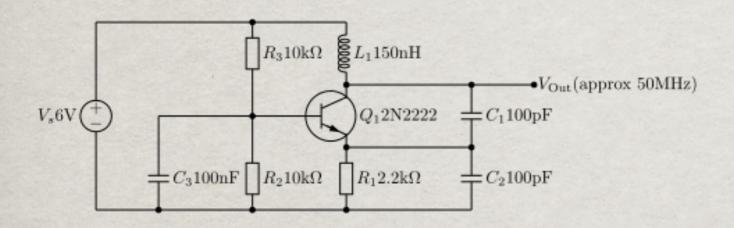


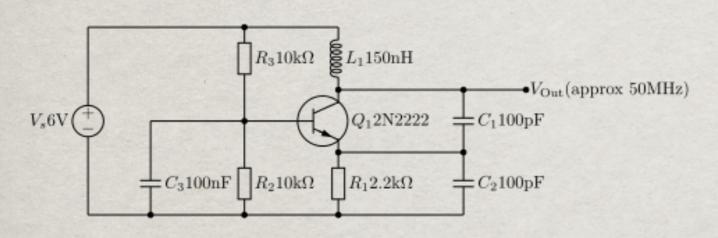




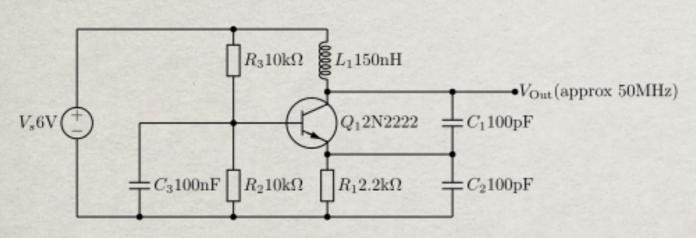




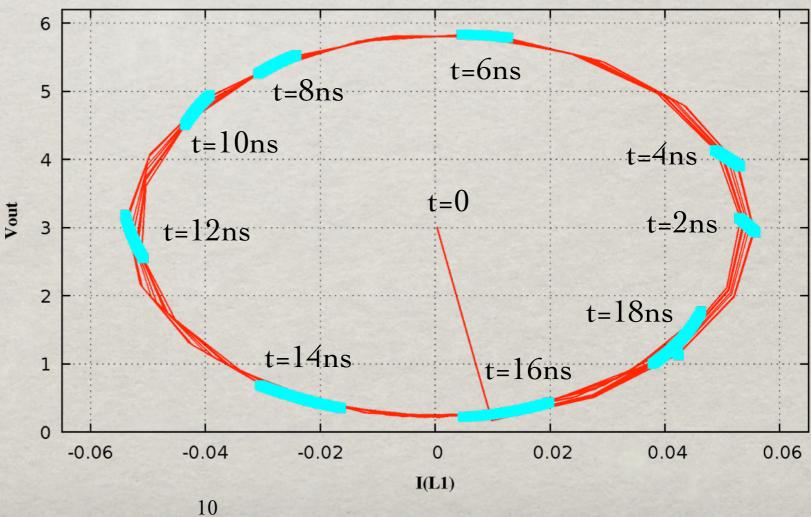


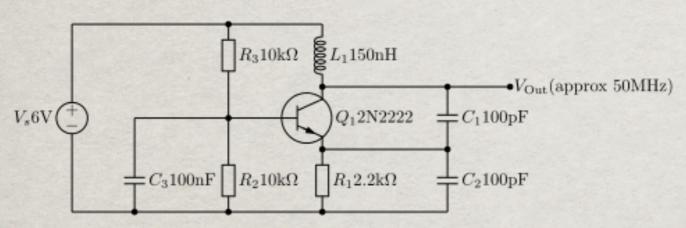


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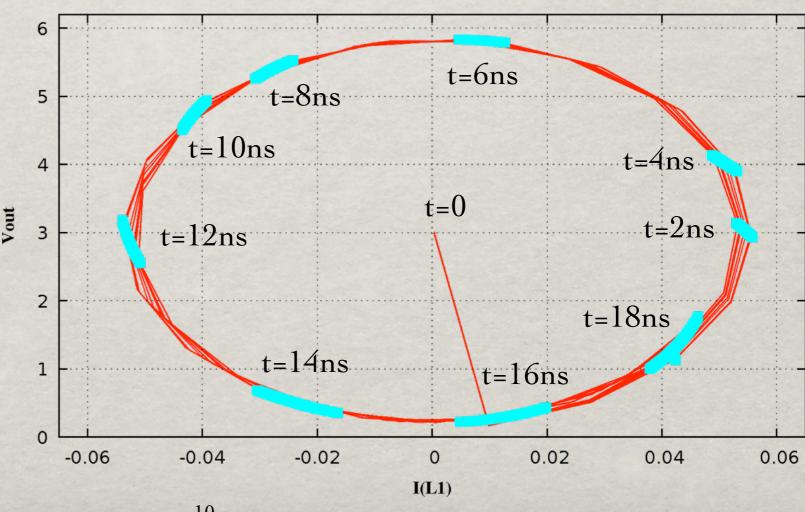


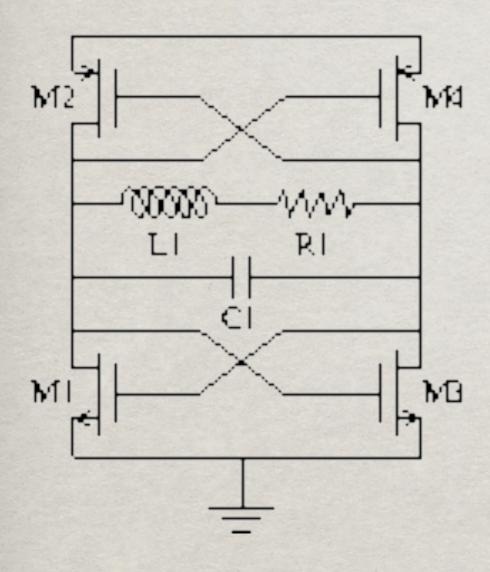


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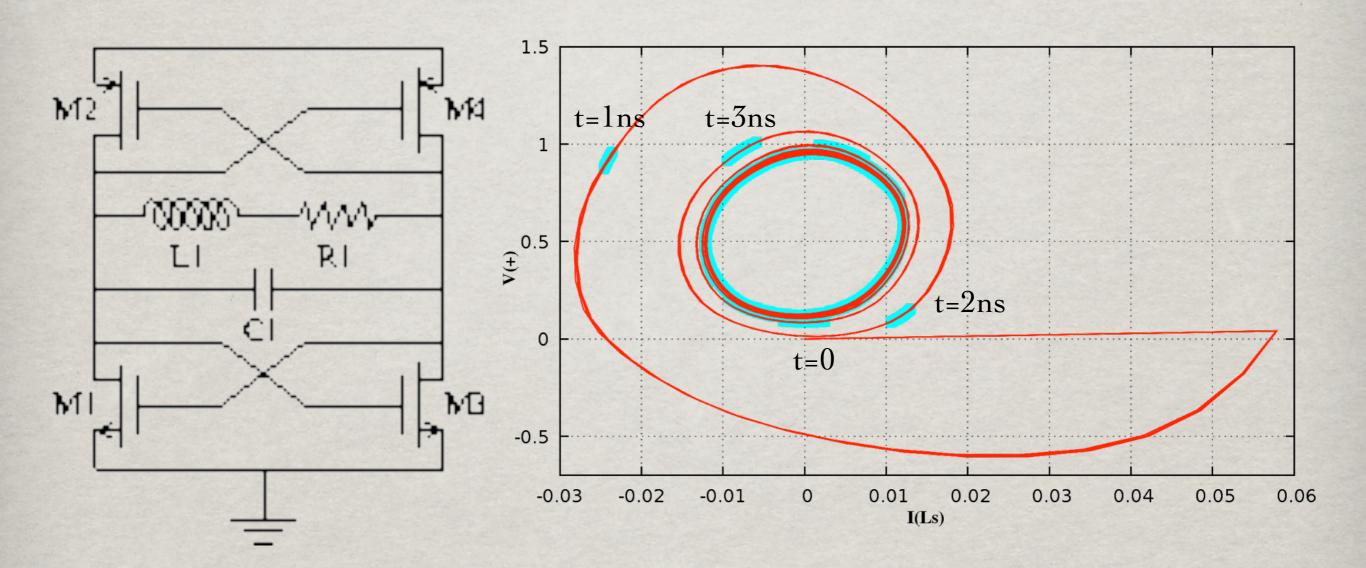
#### Observations:

- Oscillation
- No limit cycle yet
- Longer flowpipes

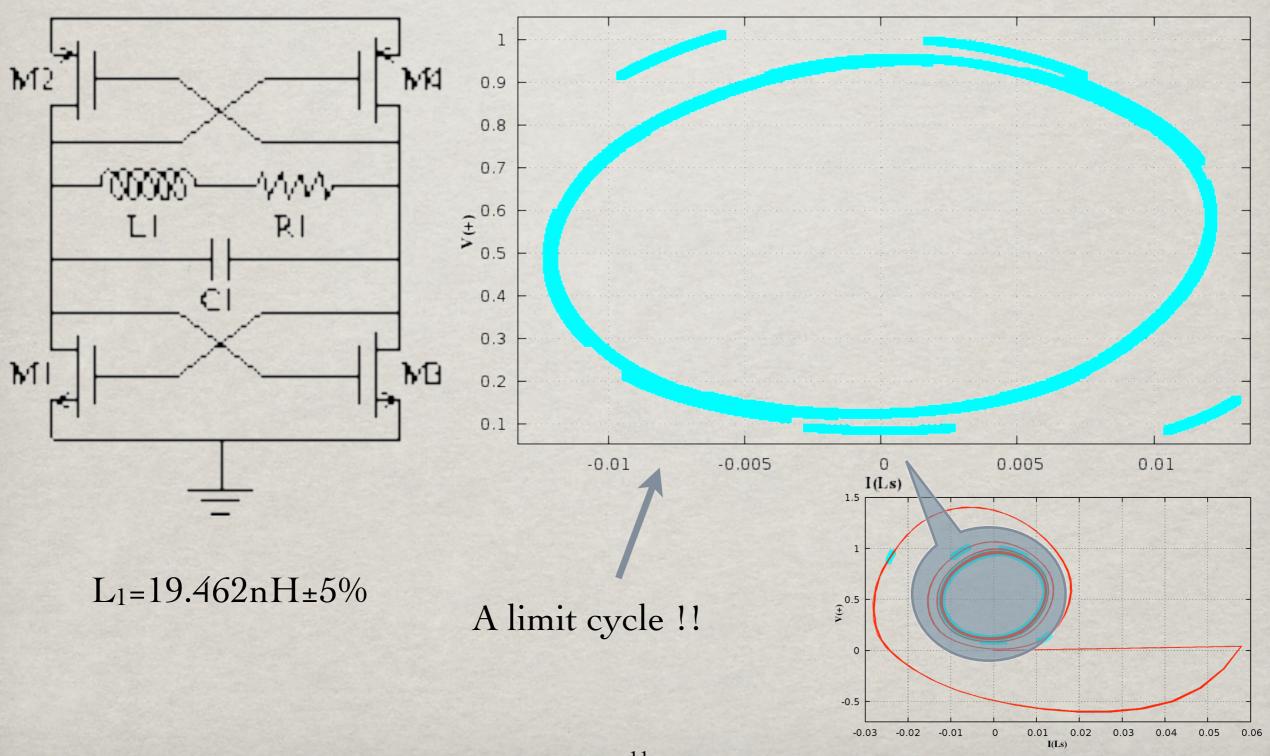


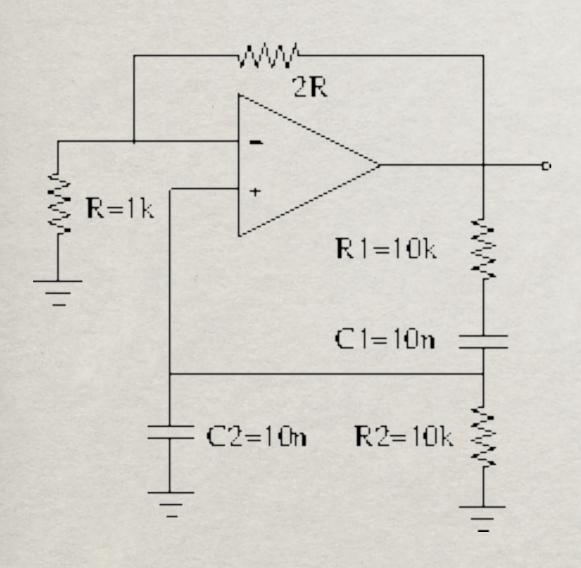


 $L_1=19.462 nH \pm 5\%$ 

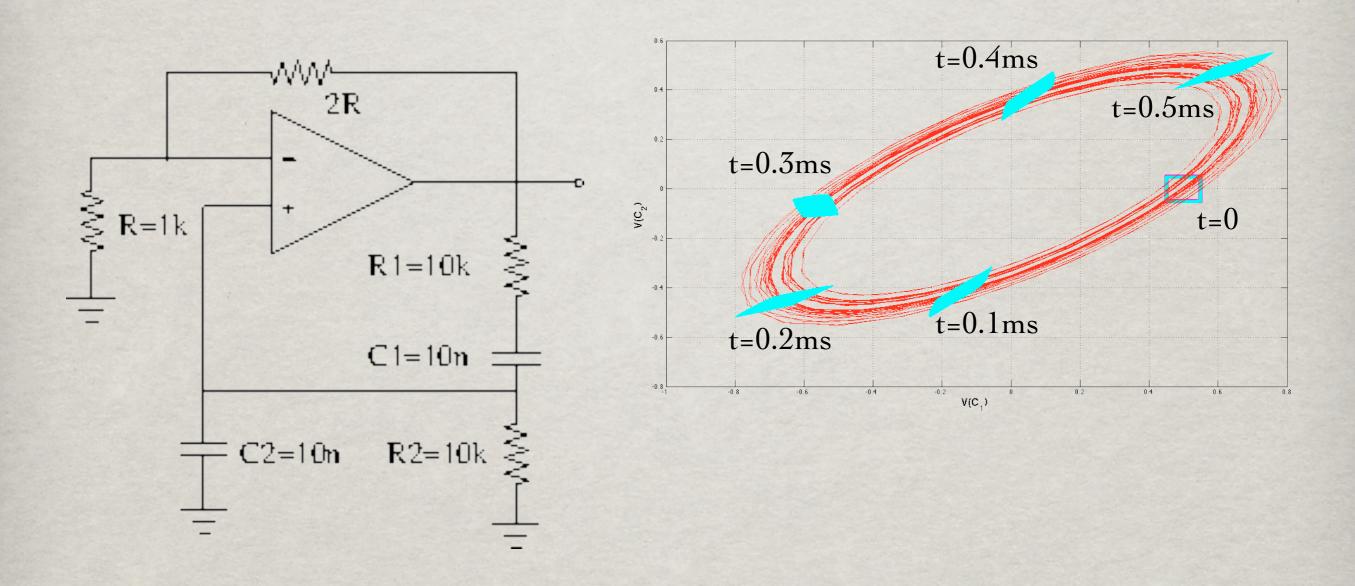


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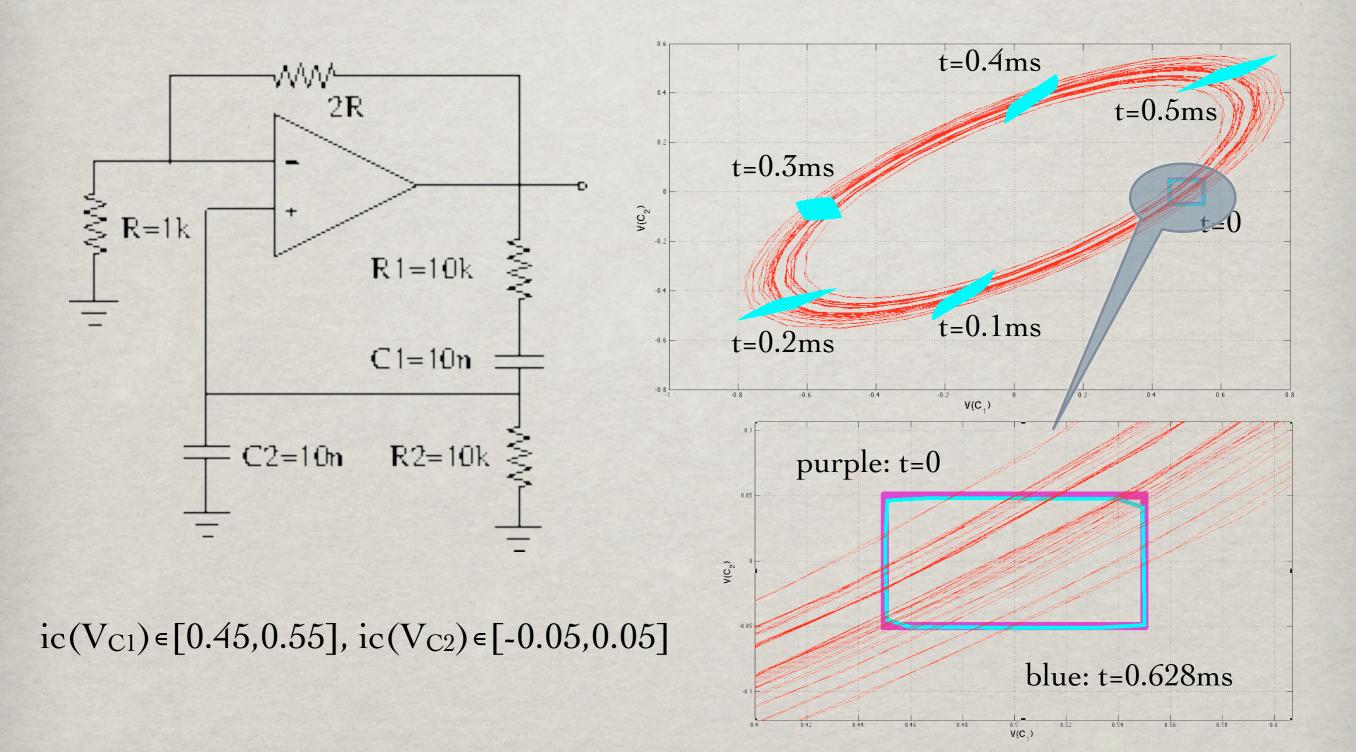




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• Enable verification of large circuits

### Q & A